

# CBCS SCHEME

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15EC63



Sixth Semester B.E. Degree Examination, Jan./Feb. 2021

## VLSI Design

Time: 3 hrs.

Max. Marks: 80

Note: Answer any FIVE full questions, choosing ONE full question from each module.

### Module-1

- Explain the nmos enhancement mode transistor operation for different values of  $V_{GS}$  and  $V_{DS}$ . (06 Marks)
  - Obtain the transfer characteristics of a CMOS inverter, mark all the region, showing the status of PMOS and nmos transistor. (10 Marks)

OR

- Explain the fabrication steps of CMOS P-well process with neat diagram, and write all the mask sequence. (10 Marks)
  - Distinguish between CMOS and bipolar technologies (06 Marks)

### Module-2

- With neat diagram, describe the design rules i) Transistor ii) wires iii) contact cut. (08 Marks)
  - Draw the Schematic and Mask Layout for the expression  $Y = \overline{AB + CD}$ . (08 Marks)

OR

- Derive the expression for the Rise time and fall time for CMOS inverter. (10 Marks)
  - Two MOS inverters are cascaded to drive a capacitive load  $C_L = 14\text{cg}$  as shown in Fig Q4(b). Calculate the pair delays  $V_{in}$  to  $V_{out}$  in terms of  $\tau$ .

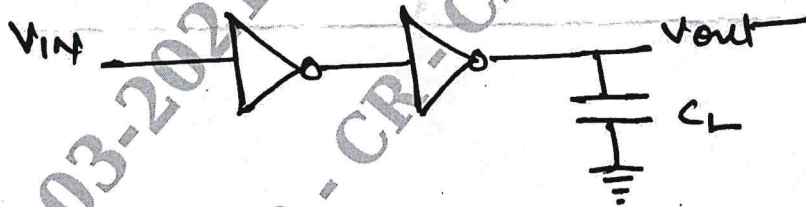


Fig Q4(b)

(06 Marks)

### Module-3

- Why do we require scaling of MOS circuits? (04 Marks)
  - Find the scaling factors for the following : (12 Marks)
    - Gate capacitance ( $C_g$ )
    - Saturation current ( $I_{ds}$ )
    - Gate capacitance per unit area ( $C_{ox}$ )
    - Carrier density in channel ( $Q_{ON}$ )
    - Maximum frequency of operation ( $f_0$ )
    - Speed power product ( $P_T$ )

OR

- 6 a. Discuss the General considerations of the subsystem Design process. (06 Marks)  
 b. Explain a standard Adder element using nmos version of adder logic. (10 Marks)

Module-4

- 7 a. Explain the multiplexer/Data selections with layout. (10 Marks)  
 b. Explain parity Generator with stick diagram. (06 Marks)

OR

- 8 a. Briefly explain Architecture of FPGA. (10 Marks)  
 b. Explain Antifuse base FPGA. (06 Marks)

Module-5

- 9 a. Explain one transistor DRAM. (08 Marks)  
 b. Explain Three Transistors DRAM. (08 Marks)

OR

- 10 a. Explain objectives of Functional Testing. (06 Marks)  
 b. Define fault model, explain the (10 Marks)  
 i) Stuck – at Faults  
 ii) Stuck – open and stuck – short Fault  
 iii) Stuck – open Fault

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